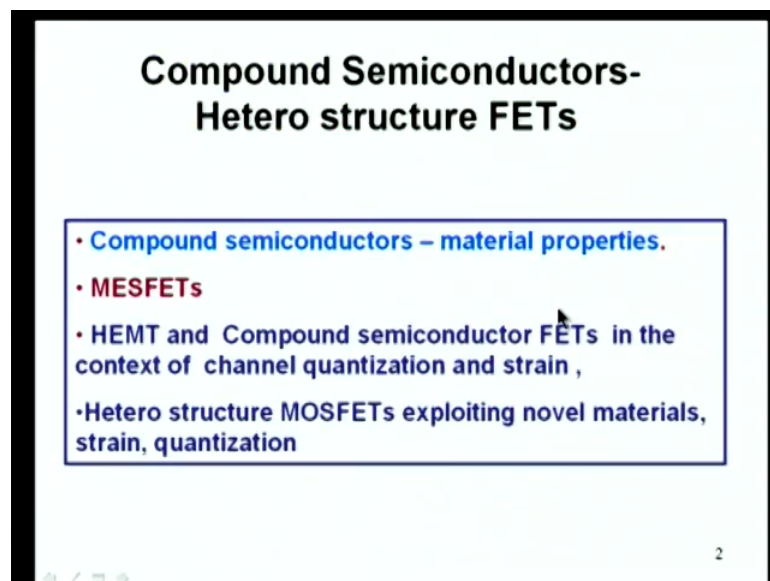


Nanoelectronics: Devices and Materials
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Indian Institute of Science, Bangalore

Lecture - 29
GaAs MESFETs: Enhancement and depletion types
Velocity Overshoot effects In GaAs MESFETs

We continue our discussion on the compound semiconductors.

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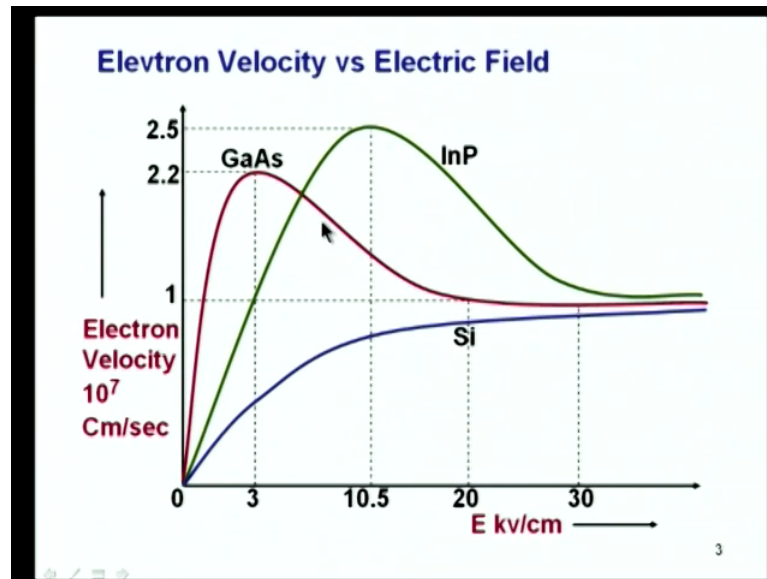
**Compound Semiconductors-
Hetero structure FETs**

- Compound semiconductors – material properties.
- **MESFETs**
- HEMT and Compound semiconductor FETs in the context of channel quantization and strain ,
- Hetero structure MOSFETs exploiting novel materials, strain, quantization

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Particularly we move on to the FETs and hetero structure FETs we have just begun our discussion.

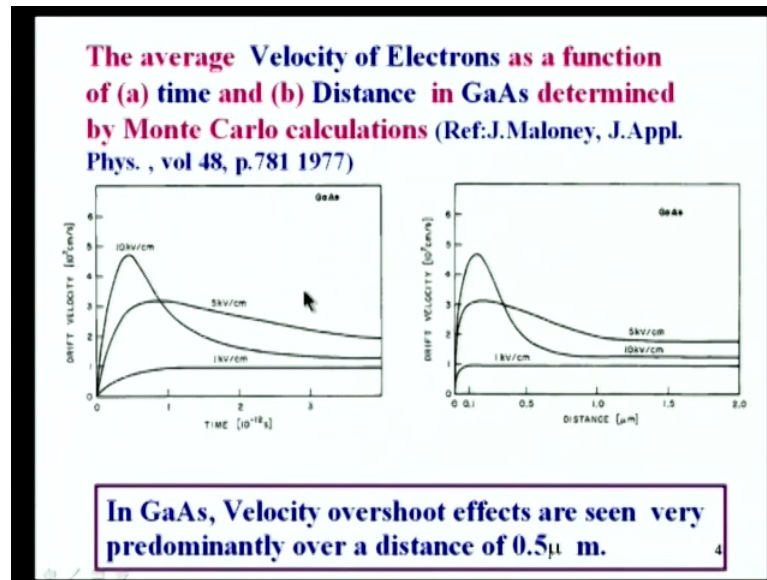
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And as we have shown that the gallium arsenide and indium phosphide have got electron velocity versus electric field totally different from that in the case of silicon we have claim that this is because of the transport mechanism the electrons tend to be in the high; high electron mobility region that is no effective mass region at a slightly lower energy and it gets transferred onto the higher mass region where the mobility falls. So, it go through that region and ultimately goes into the saturation region.

So, if you have bias the device or if the electrons enter into this high field region suddenly it does not go there straight, it will go through this portion and go there. So, due to that there will be a time interval during which the electron goes through this peak velocity.

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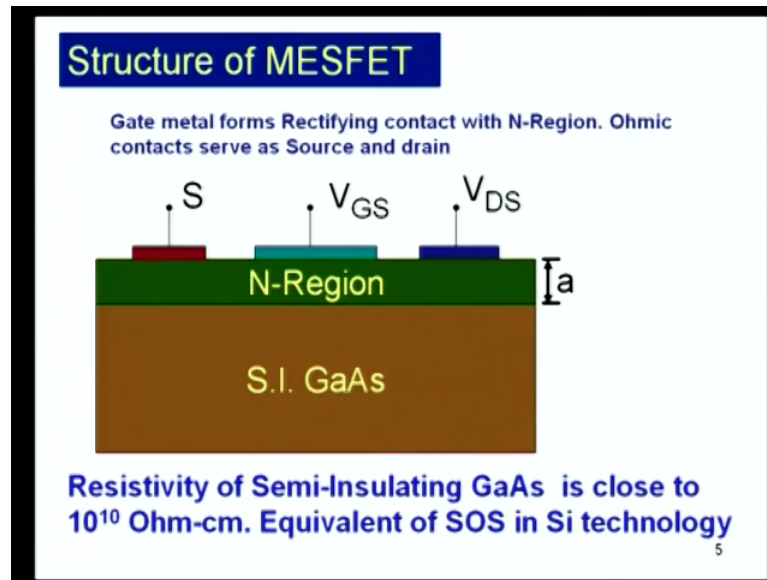


So, that is shown in this graph that is time versus drift velocity of gallium arsenide if you take if I apply 10 kV that is a saturation field at 10 kV, but in the initial couple of microseconds the velocity much higher than the saturation velocity because the electrons are located in the no mass region.

So, their velocity is high at that field, but once they acquire energy they go into the region where the mass is high. So, it saturates. So, if you convert it into distance we know that now this distance see by the time it has moved reached that velocity it has moved through this region. So, drift velocity versus the distance along the channel from the source will have the velocity like this for 10 kV. So, that would tell us that there is specific benefit for gallium arsenide devices and indium phosphide devices.

Where if you go to short channel length the over the entire region the velocity will be higher than the saturation velocity. So, that give you a higher current driving capability for a given dye device and also higher trans conductance there is a driving capability is better.

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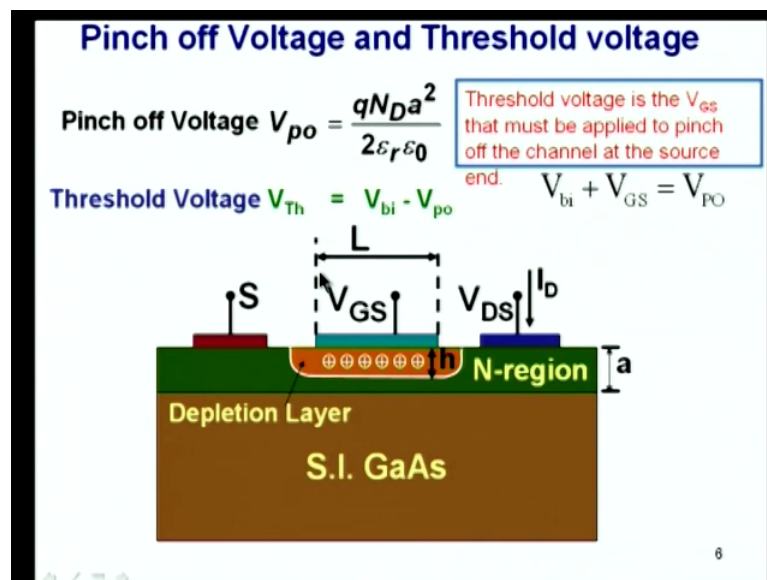
So, device which is very popularly used in the gallium arsenide material is the metal semiconductor field effect transistor rather than using the MOSFET as in the case of silicon, all the most of these gallium arsenide microwave millimeter microwave integrate circuits m I my mic. So, those devices are made up of MESFET logic circuit though there are improvements which we can discuss in the next lecture other type of devices like the HEMPT which are being attended to know. So, here I already pointed out that you have got the source and then which are ohmic contacts through the n type region which is a thin layer realized on semi insulating gallium arsenide now this contact is a gate contact in case there is no gate the between the source and drain you have got this conducting channel.

So, there will be it is equivalent of a resistance as you vary the voltage the current will vary across through the resistor now how much is the current flow depend upon the doping here and how much is the thickness of this n region suppose the thin layer is very thin the; now if you are is not there at all the full layer is available for conduction suppose in this metal semiconductor contact which is the rectifying contact which is serving as the gate is present on the top of this layer, there be there will be depletion layer below that channel below the gate, because some key contact or rectifying contact will. Now always have a depleted layer suppose due to that built in potential the depletion layer below that is completely depleting the channel the current flow between the drain and the source will be 0, because there is this is there is no careers available entirely depleted. So, if I want to bring it on condition what I have to do would be I have to reduce the depletion layer

width.

I can reduce the depletion layer with by thorough by see this metal semiconductor contact apply plus voltage to the gate depletion layer can width can open that is the level of current of flow; that means, the device can act as announcement more type of device if it is depleted with then there is a 0 gate bias alternately if the doping at thickness are such that the depletion layer width at 0 bias is 0 less than the thickness of this channel. Then even without applying gate voltage there will be current flow because some channel is open as you can see here that will be depletion type.

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For example here, the diagram that I have shown even without the gate voltage if there is a depletion layer like this of height h then the current flow with through this region between this plus charges are the depleted layers between the semi insulating layer and the depleted layer depletion layer there is a path for current flow. So, if the and 0 when the gate bias is 0, if the depletion layer width is less than this channel thickness a then the current will be the present even at without gate bias that is depletion type of device.

Now before you go into a discussion of this type of device, we will see how couple of definitions one is the pinch off voltage pinch off voltage is the voltage or the potential that must exist across the depletion layer which completely depletes that channel. So, due to the potential V_{p0} present across the depletion layer if the channel is completely depleting then there is no current flows that is pinch off that is channel is completely pinched off

from source to drain completely. So, you can see that from the standard relations from the abrupt junctions of the model the pinch off voltage will be $V_{p0} = \frac{q N_d a^2}{2 \epsilon_r \epsilon_0}$ where N_d is the doping, a is the thickness of the layer, ϵ_r is the permittivity of gallium arsenide if it is silicon it is that of silicon it is about 12.8 for the case of gallium arsenide for silicon its 12.

So, how much is that pinch off voltage depends upon the thickness and the doping of this thinner layers pinch off voltage it is higher doping pinch off voltage will be higher for a given thickness. So, now, you can see that if the built in voltage is less than the pinch off voltage the depletion layer width will be less than the channel thickness; that means, it will be normally off. So, if I have to turn off the device I have to add additional gate voltage to the built in potential. So, that the depletion layer becomes completely equal to a . So, if V_{bi} it is equal to h $V_{bi} + V_{GS}$ actually V_{GS} is should be negative because the polarity of V_{bi} is plus here and minus there, you have to add on gate voltage means actually you have to pay negative voltage. So, if I apply V_{GS} . So, that the depletion layer widens and becomes equal to a then $V_{bi} + V_{GS}$ is equal to V_{p0} .

So, what you are telling is if I apply a add V_{GS} to V_{bi} then it will be V_{p0} . So, the channel will be pinched off now the definition of threshold voltage. So, let us come back to this now suppose V_{bi} equal to V_{p0} even if your slightest voltage is applied to the gate plus voltage the depletion layer width will reduce suppose V_{bi} is less than V_{p0} , I must apply negative voltage to the gate.

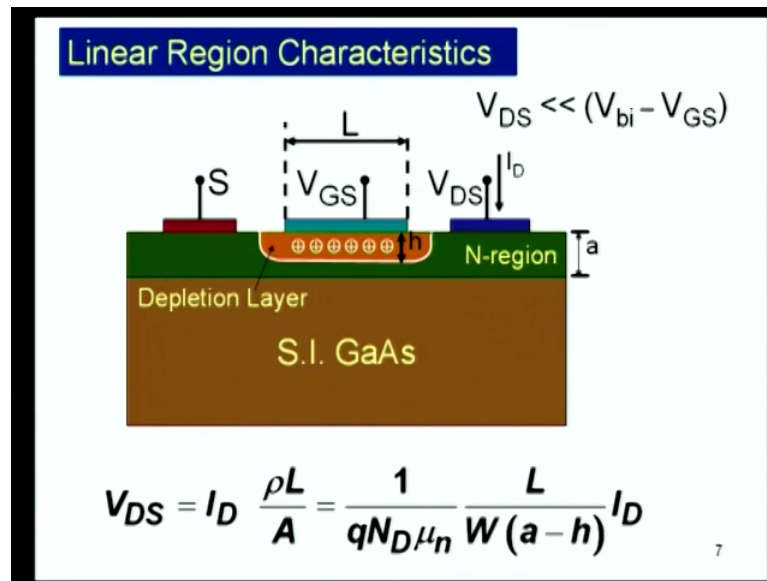
So, that depletion layer widens to turn off the device for example, when the built in voltage is 0.5 volts if the depletion layer width is h , I must add let us say and let us say d built in potential is 0.5 and V_{p0} is 1 volt then I must add 0.5 volt to the gate. So, that deplete entire channel is depleted; that means, the V_{GS} will be actually what you reply will be same polarity as the built in voltage that is gate voltage will be negative. So, if I apply 0.5 volts negative voltage to the gate then the channel will be pinched off the gate will be turned off..

So, threshold voltage is the voltage that you must apply to the gate. So, that when you apply that the potential across the channel is equal to V_{p0} . So, that V_{GS} is actually equal to $V_{bi} - V_{p0}$. So, V_{th} threshold voltage threshold voltage of the MESFET is defined as the gate voltage that I must apply. So, that the tan channel is just depleted see in the example that you have taken if V_{bi} is 0.5 and V_{p0} is 1 volt threshold voltage is 0.5

minus 1 that is minus 0.5 volts, I must apply minus 0.5 volts to turn off the device it is in the verge of turn on suppose in the V_{bi} is 0.8 volts and pinch off voltage is 0.5 volts V_{bi} minus V_{P0} is plus 0.3 volts; that means, I must apply 0.3 volts to bring it to conduction plus voltage because even without applying the if this is 0.8 and V_{P0} is 0.5 even without the gate voltage channel will be depleted I must apply plus voltage to the gates.

So, that the channel is just opening up that is a definition.

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Now, let me go into the quickly into the analysis of this device not into too great detail, but how it comes about just like in the case of MOSFET or any other FET the MESFET also have got linear region, then the try out region and the saturation region. So, if in the linear region, it behaves like a resistor that is the channel thickness is same from source into the drain end that like in the case of MOSFET the channel charge is same from source into the drain end here channel thickness is the same from the source into the drain end. So, we are talking of the drain voltage which is very much less than whatever voltage is present here V_{bi} minus V_b ; V_{GS} see for example, when V_{GS} e equal to 0 there is certain depletion layer width now V_{GS} what we have applying here is if I write just V_b ; V_{GS} , then you have to if you deplete it you must make it negative. So, if I add V_{bi} minus minus V_{GS} this is negative. So, then depletion layer with widen. So, V_{bi} minus V_{GS} is actually a total voltage present here to example if I want to give plus 0.5 minus of minus 0.1 volts that is plus 0.5 plus 0.1 0.6 volts.

So, this is actually more than the V_{bi} which you are applying here. So, then the depletion layer will be widened here. So, if the V_{DS} is very small compared to this voltage drop across this depletion layer; that means, drop from here to here train to source end e is negligible compared to this depletion layer width. So, which would mean if I go from this end to that end the depletion layer width is not changing.

So, as a result what we can say is when I apply voltage V_{DS} which is small compared to this voltage across the depletion layer, the current will be or the current voltage relationship is just like a resistor. So, V_{DS} is actually. In fact, what you are saying is doing is you are neglecting the drop between this point and this point assuming that this is very close in contact with this gate region.

You cannot keep in touch with this gate region because then it will sort there must be some finite space ID into r is the voltage drop across the resistor r is ρL by a ρ is the resistivity resistivity of the channel L is there ρ is $1/\sigma$ is qN_D into μ_n . So, this is actually this is actually the whole term is ρ or one by σ length area of cross section for the current flow in the along the channel is channel thickness channel thickness into width cross section if you take that is thickness into the widthness perpendicular to this plane of this one. So, area of cross section to the current flow is a minus h that is that thickness into w . So, you can see that w into a minus h is the area of cross section. So, this ρL by a into ID is the voltage drop.

So, I just rewrite that we will develop on that what is A ? A can be correlated to the pinch off voltage through this relationship so. In fact, I can say that a is proportional to square root of V_{P0} and what is h ? H will be see V_{P0} is actually the voltage total potential present across the channel when the its depleted depletion layer width is equal to a now in this particular situation the voltage present across this is V_{bi} minus V_{GS} that is a voltage. So, if h is the depletion layer width when the voltage is V_{ba} minus V_{GS} then you can use the same equation V_{bi} minus V_{GS} is equal to qN_D into qN_D into h^2 . So, you can use that relationship to get that depletion layer width like this. So, this is related V_{P0} and h is related V_{bi} minus V_{P0} that is all V_{G0} that is what you have to remember ok.

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Linear Region Analysis

$$V_{DS} = I_D \frac{\rho L}{A} = \frac{1}{qN_D\mu_n} \frac{L}{W(a-h)} I_D$$
$$\therefore I_D = \frac{qN_D\mu_n W a}{L} \left(1 - \frac{h}{a}\right) V_{DS}$$

In Terms of Channel Conductance G_0 ,

$$I_D = G_0 \left(1 - \frac{h}{a}\right) V_{DS} \quad \text{where, } G_0 = \frac{qN_D\mu_n (W a)}{L}$$

So, V_{DS} is this one I have rewritten this equation whatever we explained now; now I_D therefore, I can write I_D by re writing this taking to the other side $q N_D \mu_n$ into W into a divided by that this quantity.

I rewritten that what is this quantity this is σ divided by L channel length into cross section cross section of the channel when it is fully open w into a is actually the entire cross section w is the depth a is the thickness. So, W into a is the cross section. So, if you see this; this is the conductivity, conductivity into area divided by L that is a conductance instead of resistance it is conductance $q N_D \mu_n$ into V and then. So, that you can write it as and I just pull that out a . So, you get this one. So, in terms of the channel conductance G_0 this is G_0 I can write I_D is equal to G_0 into $1 - \frac{h}{a}$ by a why we are writing like this is you know that a will be proportional to root of V_{P0} and because if V_{P0} is present depletion layer width is a and if the voltage across the depletion layer width is $V_{bi} - V_{GS}$ h is a depletion layer width.

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Depletion Layer Width "h" Depends Potential Across gate ($V_{bi} - V_{GS}$)

Applying abrupt junction model,

$$h = \sqrt{\frac{2\epsilon_r\epsilon_0 (V_{bi} - V_{GS})}{qN_D}}$$

The slide features a diagram with two green boxes: "Depletion Layer Width 'h'" on the left and "Potential Across gate ($V_{bi} - V_{GS}$)" on the right, connected by a red arrow labeled "Depends". Below this, the text "Applying abrupt junction model," is written in red. The equation for h is shown in black. A small inset image of a man in a white shirt and tie is visible in the bottom right corner of the slide frame.

So, you can write this as ratio of the 2 will be square root of V_{bi} minus V_{GS} divided by V_{P0} that is a thing h is equal to qN_D see $qN_D h^2$ divided by twice of epsilon r epsilon 0 is the voltage drop across the depletion layer that is a standard equation if your V_{P0} that will be way where a is equal to this whole term into V_{P0} h is equal to this whole term into whatever voltage is present across the depletion layer that is V_{bi} minus V_{P0} . So, if I take a by h this term will cancel I am sorry; if I take h by a ; this term will cancel and h by a will be square root of V_{bi} minus V_{GS} by a .

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Pinch Off Voltage

Depletion Layer Width 'h' = Channel Thickness 'a'

The channel is fully pinched off and the current will be zero. This potential is termed as Pinch Off Voltage V_{po}

$$V_{po} = \frac{qN_D a^2}{2\epsilon_r\epsilon_0}$$

The slide features a blue box with the title "Pinch Off Voltage". Below it, two green boxes are connected by an equals sign: "Depletion Layer Width 'h'" and "Channel Thickness 'a'". A white box with a red border contains the text: "The channel is fully pinched off and the current will be zero. This potential is termed as Pinch Off Voltage V_{po} ". The equation for V_{po} is shown in black. A small inset image of a man in a white shirt and tie is visible in the bottom right corner of the slide frame.

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Therefore, $a = \sqrt{\frac{2\epsilon_r\epsilon_0V_{po}}{qN_D}}$

Substituting "h" and "a" in I_D we get,

$$I_D = G_0 \left(1 - \sqrt{\frac{V_{bi} - V_{GS}}{V_{po}}} \right) V_{DS}$$

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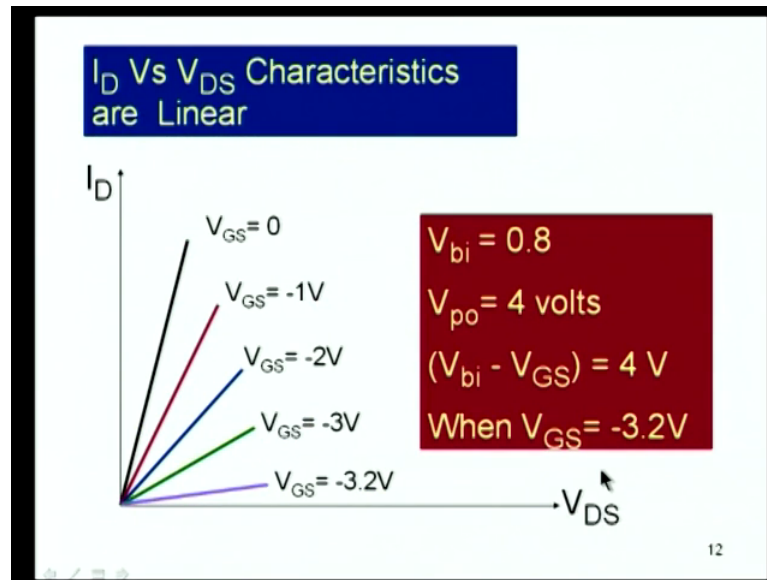
So, V_{p0} is that a is that. So, substituting both the things as I just pointed out I_D is equal to G naught into one minus h by a into V_{DS} that is what we saw; now for h by a ; a is this quantity h is a same quantity, but replaced by V_{bi} minus V_{GS0} .

So, h by a will be this. So, this is the I_D versus V_{DS} then V_{DS} is small compared to be the voltage drop across the depletion layer implying the resistance is actually it behaves like a resistor between these portions the depletion layer width is remaining the same thing because the drop from here to here is not changing we have V_{DS} is very small there is some. So, that is the thing.

Now if I take the I_D characteristics of this small MESFET what will happen this is constant it is actually channel conductance when it is fully open and for a given voltage this is constant. So, if I vary I_D if I vary V_D I_D will vary linearly V_{GS} is actually negatives of this will add on. So, if I keep on increasing the V_{GS} negatively this term become larger and larger this become smaller and smaller depletion layer width become wider, wider and wider. So, the channel conductance total conductance will become reduced current will reduce.

So, far given a gate voltage there will be linear relationship. So, V_{GS} equal to 0 $1 - \frac{V_{bi}}{V_{p0}}$ into V_{DS} .

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So, if I increase the gate voltage the depletion layer width increases channel thickness available current flow will reduce. So, current is reduced that. So, you can see several linear characteristics you can obtain by keeping on increasing the V_{GS} till you spins out the channel completely when you spins out the channel completely current will be 0. Now what will happen if I increase the drain voltage further.

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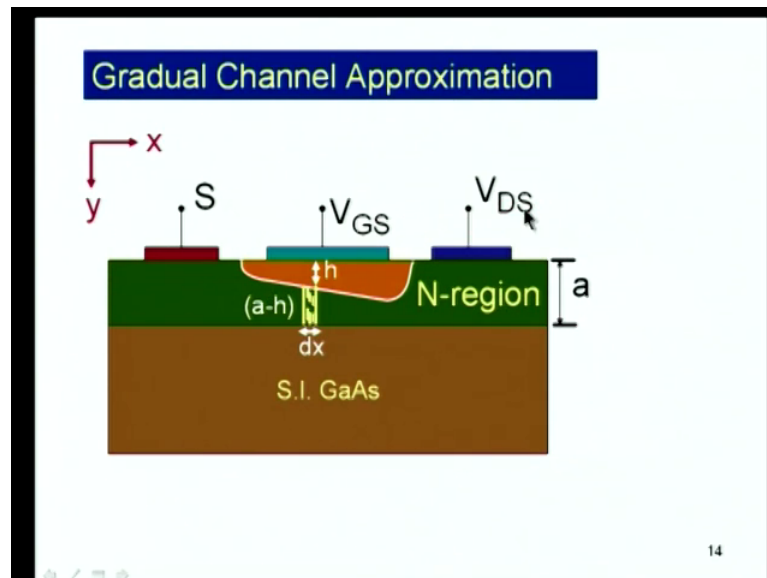
As V_{DS} becomes larger and comparable to $(V_{bi} - V_{GS})$, the potential drop across the depletion increases from $(V_{bi} - V_{GS})$ to $(V_{bi} - V_{GS} + V_{DS})$ as we move from the *Source End* of the channel to its *Drain End*

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As V_{DS} becomes larger and comparable to $V_{bi} - V_{GS}$ what we are telling is I increase the V_{DS} initially when the V_{DS} is small the depletion layer is constant

everywhere.

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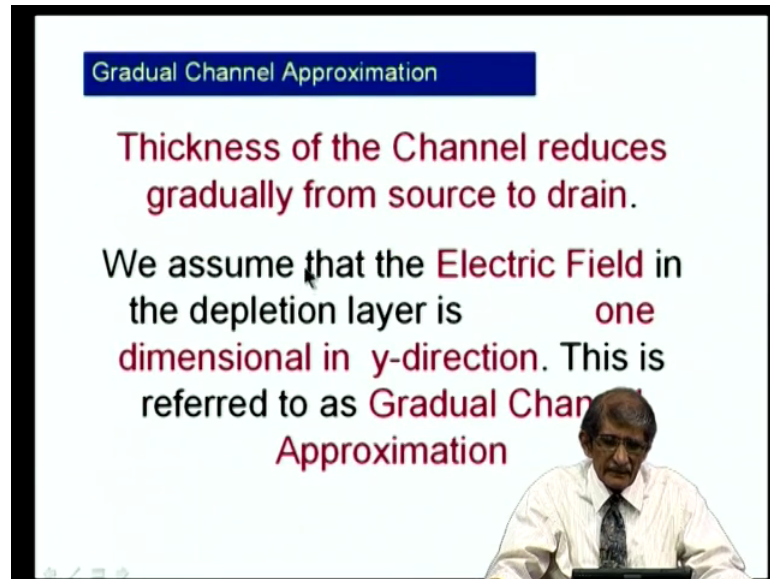
Now, as I keep on increasing the voltage that drop from the drain to the source region becomes comparable to the depletion voltage across the depletion layer width depletion layer the voltage across the depletion region was V_{bi} minus v_{gs} . In fact, if you take the magnitude it is V_{bi} plus magnitude of V_{GS} . So, that is plus here minus here now if you move in this direction there is radiation plus voltage here. So, if this is V_{bi} minus V_{GS} from here to here.

If I take the drain end the voltage from here to here will be for example, if it comes from here V_{bi} minus V_{GS} rise from here to here from here to here further we V_{DS} ; V_{DS} rise is there. So, total voltage drop across the depletion layer will be V_{bi} minus V_{GS} which is the drop there plus the drop across the channel that is exactly what you did in the case of MOSFET. So, voltage drop across the depletion layer at this edge will be more than the voltage drop here by an amount equal to the V_{DS} even in the linear region, it will be there, but it is negligible compared to this voltage.

So, because the voltage drop is more here you can see the depletion layer width will be something here h naught a ; a move here it will keep on increasing. So, that is what we are saying here at the drain end the V_{DS} as V_{DS} becomes larger and comparable to V_{bi} minus V_{GS} that is a voltage that is present at the source end then the potential drop across the depletion layer increases at the source end at the source end from V_{bi} minus V_{GS}

V_{GS} to $V_{GS} - V_{GS} + V_{DS}$ at the drain end.

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As you move from the source to the end of the channel. So, as a result depletion layer width will be wider the thickness of the channel it reduces gradually from the source to drain because potential drop here is something here it is more by an amount equal to V_{DS} . So, depletion layer gradually decreases increases from here to here and the channel thickness decreases from here to here.

So, it is equivalent of a resistor if the resistor is like that if the resistor is like this constant width when you increase the voltage current will increase linearly suppose if the resistor becomes narrow at the drain end due to the depletion layer width the effective resistance of the channel increases. Therefore, even if the resistance are constant current would have increased linearly, but because as you increase the drain voltage the shape of the resistance keeps on changing like this the resistance of the channel of increases as you increase the drain voltage because the resistance increases with the drain voltage the current will not increase linearly with the drain voltage.

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Assuming that ohms law holds good, the voltage drop 'dV' across the length 'dx' can be written as follows

$$\frac{I_D dx}{qN_D\mu_n W [a - h(x)]} = dV$$

Integrating we get the Total Voltage Drop

$$\int_0^L \frac{I_D dx}{qN_D\mu_n W [a - h(x)]} = \int_0^{V_{DS}} dV$$

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As a result what happens is you get a I am sorry, just you get a you as a result of that there is deviation from linearity and ultimately, the current will saturate current will saturate when this particular region thickness becomes very very small here; drain end when the depletion layer almost reaches to this end of the channel thickness, it is almost closes when it almost closes the resistance becomes very very large, it cannot close anymore further it in the small gap there.

So, current in the control wave whatever is flowing through that small gap if it you can see if the current tends to increase beyond that points the drop would increase if the drop increases the depletion layer width is wider if it increases then the it will close the channel if it closes the channel current will tend to fall. So, depletion will open.

So, what we are telling is a dynamic equilibrium will reach where channel will come to close almost closing region, but not completely closing. So, that to allow whatever current is entering here to go through that thing. So that means, from here to here, the drop is actually equal to $V_{GS} - V_{bi} + V_{DS}$ that will drop across the depletion layer and drop across a depletion layer is just sufficient to close the channel; that means, the total voltage across the depletion layer. Now will be $V_{bi} - V_{GS} + V_{DS}$ that should be equal to pinch off voltage V_{P0} . So, when $V_{bi} - V_{GS} + V_{DS}$ becomes equal to V_{P0} the current will saturate that is all the principle that is involved here. So, that is idealistic model there were changes in that, but still we can use it as a for long channel devices without any hesitation. So, what we are going to do is quickly see.

So, now what we know is depletion layer widens channel becomes narrower and narrower at the drain end therefore, I_D V_{Dd} relationship is no longer linear because the resistance keeps on increasing, but when the voltage drop across the channel reaches a certain value that is called a V_D sat at that point the depletion layer almost closes this V cannot the voltage cannot increase beyond that point because then the depletion layer if it closes fully current will tend to fall. So, the dynamic at the dynamic equilibrium you reach the V_D sat such that the depletion layer at the drain edges just closed just about to close; that means, voltage drop across the gate and this channel end is V_{P0} which would mean that V_{P0} is equal to V_{bi} minus V_{GS} plus V_D sat that is a condition for saturation current you can quickly run through this.

So, now actually this is you take this as a gradual channel approximation because when analyzing and finding the depletion layer width you still use one dimensional equation along this letting x indicating that the 2 dimensional if it is; are not present here in this direction. So, that is called gradual channel approximation meaning the channel thickness changes gradually from source to drain end or the voltage change here is very gradually go along with the channel length or in other words L_{tp} if it is in this direction is small compared to that if it in the vertical direction that is like in the case of MOSFET where we also talked of gradual channel approximation.

Now, with this understanding and just quickly run through the derivation not going through the very detailed. So, all that we have to see is use the same equation whatever we are using take a small width same as V is equal to I into r what we do is take a small width d of x determine what is the drawback across that and at any x x is in the direction at any x take t of x channel length d of x what is the voltage drop across that integrate that from x equal to 0 to x equal to L channel length L and voltage equal to V_{bi} minus v_{gs} .

Here to V_{bi} minus V_{GS} plus V_D V_{DS} that will give the i_{dbd} characteristics over the entire region from linear to the saturation region. So, what your voltage drop across this for a given I_D i_D into ρ into d of x divided by area of cross section, so that ρ is of course, the channel resistance which is one by $q \mu N_d$ and area is w into d of x I am sorry w into a of a minus h . So, voltage drop across d of x can be written in this fashion I_D into d of x its I_D into L divided by σ that is I_D into ρ is one by this divided by area; area is w into a minus h of x a minus h of x is thickness w is the width w into a minus h is the area of cross section.

So, you all that you have done is I_D into ρd of x divided by area that is a voltage drop across that now what you do is all that you have to remember is a is related to root of V_{P0} h minus of x is related to the voltage drop at x across this that will be that will be actually whatever voltage present here plus V of x there V_{bi} minus V_{GS} ; V_{GS} plus V of x . So, it should be proportional to square root of that voltage. So, that is what we do here now integrate it from V ori from source into the drain end this x 0 to L .

That is what we did when you do that substitute for a and h of x in terms of the V_{P0} and what is the voltage present across the depletion layer we have h of x is a depletion layer at any x net width of that depends how much is the voltage across the depletion layer that is V_{bi} minus V_{GS} plus V of x . So, same thing I have written.

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$$\therefore I_D L = q \mu_n N_D W a \int \left(1 - \frac{h}{a}\right) dV$$

$$I_D = G_0 \int_0^{V_{DS}} \left(1 - \sqrt{\frac{V_{bi} - V_{GS} + V(x)}{V_{po}}}\right) dV$$

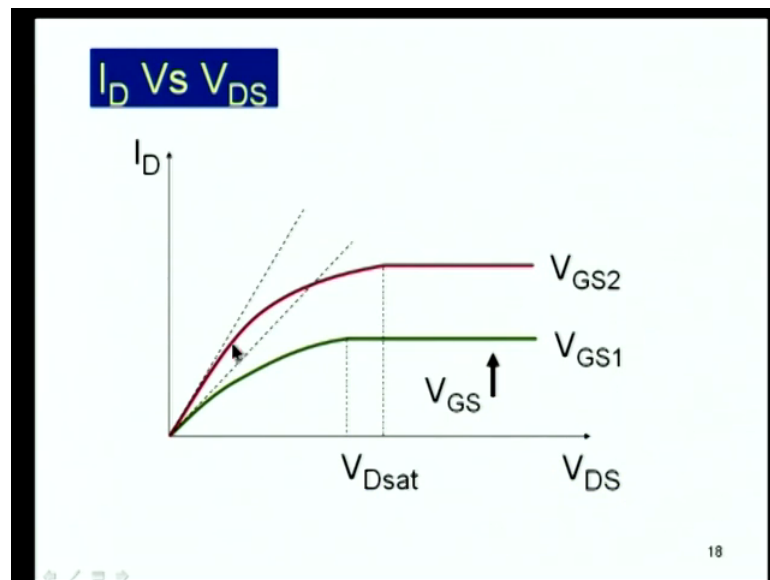
$$I_D = G_0 \left[V_{DS} - \frac{2}{3\sqrt{V_{po}}} \left\{ (V_{bi} - V_{GS} + V_{DS})^{3/2} - (V_{bi} - V_{GS})^{3/2} \right\} \right]$$

Integrating I_D into L with that quantity I have nothing no changes just read it on the whole thing because I can pull all these in front to the right hand side integral left hand side is I_D into L right hand side you get this term substituting for h and a in terms of the voltage across the depletion layer is this one at x voltage at across the entire layer or pinch off will be V_{P0} all that you did this is G naught I put L down this that is G naught conductance into this quantity integrate that and not go through that quickly that is the integral value.

So, you can see that if this term were not present V_{DS} is this term is negligible I would have got I_D verses V_{DS} linear proportional to conductance, but with the gate bias there is

a term which is reducing that. So, if you apply like reverse bias to the gate this value will go down and we saw the linear region that characteristic or like this, just I am skipping going back to show that linear region, but when the drain voltage becomes large enough drain voltage becomes large enough this term becomes smaller and larger and larger. So, for a given gate voltage for a given gate voltage if I increase V_{DS} you can see that that will result in reduction of this term that is it will not increase as much as it would if this were not there it would have increased linearly, but because of this increase in V_{DS} the current will not increase proportional to V_{DS} , but it will deviate from linearity into non-linearity when and when V_{DS} this entire term becomes equal to V_{P0} at V_c this at voltage at the drain end of the channel when that becomes equal to V_{P0} the current saturates ok.

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So, you can see that characteristic goes on linear from linearity than when that V_{Dsat} ; at V_{Dsat} this voltage which is the voltage drop across this voltage which is the voltage drop across the depletion layer at the drain end h becomes equal to a actually at that then at that point that is V_{P0} , then you get saturation.

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I_D saturates When channel is pinched off at $x=L$

Therefore substitute $V_{bi} - V_{GS} + V_{DS(sat)} = V_{po}$
 In the expression for I_D and noting that $V_{Th} = V_{bi} - V_{po}$
 we obtain the drain saturation current

So, that is the situation that you have got. So, I_D saturates when the channel is pinched off at x equal to L this almost closes that therefore, $V_{bi} - V_{GS} + V_{b d sat}$ that is the voltage drop across the depletion layer $V_{bi} - V_{GS}$ is voltage drop here plus voltage drop $V_{D sat}$. So, when that becomes equal to $V_{P 0}$ this channel closes that is the drain voltage at which current saturates. So, that is what we have plotted here $V_{D sat}$ is given by this is given by this for a given gate voltage $V_{D sat}$ is rate is determined from the applied voltage gate voltage and the pinch off voltage.

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Eqn. valid for both Enhancement and Depletion Mode Devices,

$$I_{DS} = \frac{\mu_n \left(\frac{\epsilon_r \epsilon_0}{a} \right) W}{2L} (V_{GS} - V_{Th})^2$$

For Analysis Refer: MK Achuthan and K.N. Bhat "Fundamentals of Semiconductor Devices" Tata McGraw – Hill, 2009 2nd Reprint

So, you can actually I am not going through that you can actually simplify that and write the whole thing in terms of threshold voltage because threshold voltage actually is actually V_{bi} minus V_{P0} . So, if I take V_{Dsat} I mean this condition V_{Dsat} equal to V_{b0} minus V_{bi} .

I take this write see V_{Dsat} is equal to as I write it in terms of the threshold voltage V_{Dsat} here is equal to take the whole thing to the right hand side, then you have got V_{Dsat} equal to V_{GS} minus V_{bi} plus V_{P0} or in other words.

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$$V_{bi} - V_{GS} + V_{Dsat} = V_{P0}$$

$$V_{Dsat} = V_{P0} + V_{GS} - V_{bi}$$

$$= V_{GS} - \underbrace{(V_{bi} - V_{P0})}_{V_{th}}$$

$$= \underline{V_{GS} - V_{th}}$$

You can see that the V_{bi} minus V_{GS} plus V_{Dsat} when that happens that is V_{P0} now what is V_{Dsat} is equal to V_{P0} minus V_{GS} I have taken it that side minus V_{bi} which is actually equal to V_{GS} minus V_{GS} minus this is V_{bi} V_{P0} this will be 0. So, what is this quantity that is V_{GS} minus V_{th} ? So, what you are telling is in the case of MESFET also the saturation voltage the drain situation voltage is equal to V_{GS} minus V_{th} threshold voltage when the drain voltage equals to V_{GS} minus V_{th} the current saturates this exactly the same thing.

That you had in the case of MOSFET in MOSFET also the drain current saturates drain current saturates when V_{GS} equal to V_{DS} equal to V_{GS} minus V_{th} . So, that is what. So, that is a nice thing about that. So, you can actually by substituting that term here V_{bi} minus V_{GS} V_{Dsat} or V_{Dsat} is equal to V_{GS} minus V_{th} and substitute it here use binomial theorem and simplify you get the I_D verses V_{GS}

relationship transfer characteristics exactly same as that of the MOSFET that is a very interesting see this drain saturation current when we use that relationship that is $V_{D sat}$ is equal to V_{GS} minus $V_{threshold}$ which we have found it is to be true in the case of the MESFET also then you substitute in that equation that we derived and some approximations you do.

You will get i_{ds} is equal to μ_n some capacitance into w by twice L at V_{GS} my $V_{threshold}$ whole square this exactly the same characteristics transfer characteristics of the MOSFET in the saturation region what is in the MOSFET i_{ds} is equal to μ_n see oxide; oxide capacitance per unit area into w divided by twice the channel length into V_{GS} minus $V_{threshold}$ whole square. Here all that you have to do is you can use the same equation as the MOSFET when you are to define threshold voltage as V_{bi} minus V_{VP0} that definition of the threshold voltage is different here then.

So, the saturation drain current is related to this V_{GS} minus threshold whole square into this c capacitance; capacitance of the channel instead of c_{oxide} per unit area you have got capacitance of the channel what is this ϵ_r is the permittivity of the gallium arsenide ϵ_0 divided by thickness instead of oxide thickness you have got channel thickness instead of oxide ϵ_r , you have got ϵ_r of gallium arsenide we can see for this even if the mobilities are the same thing if I take the MOSFET if I take the MOSFET. And if the materials are the same thing this will be oxide cap permittivity and this is the permittivity of gallium arsenide which is about four three times larger than that of oxide.

So, for the same thickness as the oxide you will get drain current higher if drain get current higher you will get the trans conductance also higher what is trans conductance ΔI_D by ΔV_{GS} . So, if this quantity is large trans conductance will large, but we are telling is if I use a MESFET you can get the driving capability and trans conductance better than that of MOS; MOSFET because ϵ_r is much higher compared to ϵ_{SiO_2} this is we are talking of the same thickness of oxide and same thickness of the channel. Now if I am using instead of silicon if I am using gallium arsenide in addition I have got this term which is much larger than that of silicon plus when I go to short channel MOS devices when the gallium arsenide you will have enhanced velocity enhancement effect due to velocity overshoot effects.

So, that tells you that gallium arsenide is a very good candidate for high frequency

operation. So, this is a nice thing you do not have to remember anything else for saturation region characteristics of the MESFET replace the oxide with the c channel. So, from this point of view if I want to increase that trans conductance or increase the drain current for a given voltage I can achieve it not nearly with the high mobility I can reduce the channel thickness and get that. But notice that if I reduce the channel thickness your threshold voltage will also change just like the MOSFET in the case of MOSFET your threshold voltage depends upon the oxide thickness.

Here also they threshold voltage will depend upon the channel thickness and doping, because threshold voltage depends upon V_{bi} which depends upon the barrier height V_{bi} minus V_{P0} . So, threshold voltage depends upon pinch off voltage pinch off voltage as you can recall depends upon that is been pinch off voltage depends upon channel thickness thinner the channel thickness smaller will be the pinch off voltage higher the doping higher the doping or.

If you can see for a given thickness or if you see V_{P0} is equal to $qN_D a^2$ by that for a given thickness if I increase the doping for a given thickness V_{P0} will also go up, so it is a combination of the doping and the thickness exactly like in the case of the MOSFET increase the channel doping threshold voltage goes up if I increase the oxide thickness threshold voltage goes up same thing holds good here all the things that we talk of for the MOSFET increase holds good. So, the theme here will be to go to thinner; thinner channel thicknesses and maybe go to higher doping concentration when you reduce the thickness because after all the pinch off voltage depends upon the product of n_d and thickness square. So, if I change the thickness it has accompanied by the doping if I reduce the thickness it has to be accompanied by increasing the doping. So, that I get the same V_{P0} that will be a bad news because.

If I go to thicker thinner layer if I have to increase the doping concentration which is necessary for that the resistance is less you your V_{P0} will go up V_{P0} can be controlled, but if I increase the doping mobility will fall. So, that is one thing one must remember now. So, this is a transfer characteristic. So, you can have normal people think that you cannot get in the j FET or a MESFET you cannot get its always depletion depleted mode depletion mode people think that you can see incase a threshold voltage make positive I can make the how can I make the threshold voltage positive threshold voltage is V_{bi} minus V_{P0} if V_{bi} is larger than the V_{P0} threshold voltage is positive; that means, I have to apply a plus voltage to turn on the device. So, you can get enhancement type of

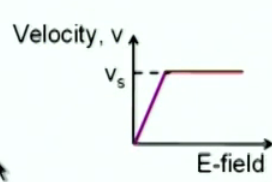
devices with the MESFET by adjusting the doping or by adjusting the thickness or ultimately by adjusting the threshold voltage, you can get positive if I have a thick layer, then usually it will not be depleted with the built in potential in that case, it will be you have to apply negative voltage to turn off the device.

That is a depletion type. So, usually when they talk of the effect they talk of thick layers of the channel then it will be mostly depletion; depletion type of device, but today in the gallium arsenide integrated circuits they talk of enhancement type of device as the driving device and depletion type of device as the load device is a load resistance or le load device you can operate it at 0 bias by connecting gate to the source you can see there is a point of operation. So, you can use it as a 2 terminal device by connecting their gate and the source and use it as the load resistance and this is the driving resistance. So, n channel devices can be made integrated circuits are be made logic circuits using the gallium arsenide FET no that is we see few things before I close down today few items I want to (Refer Time: 45:51).

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In short channel MESFETs where electric field is high it has been shown (with piecewise linear approximation for the velocity field characteristics) that I_{DS} can be expressed by the following equation, (by Michael Shur)

$$I_{DS} = 2c_s W v_s \frac{(V_{GS} - V_{Th})^2}{V_{po}}$$

$$c_s = \frac{\epsilon_r \epsilon_0}{a}$$


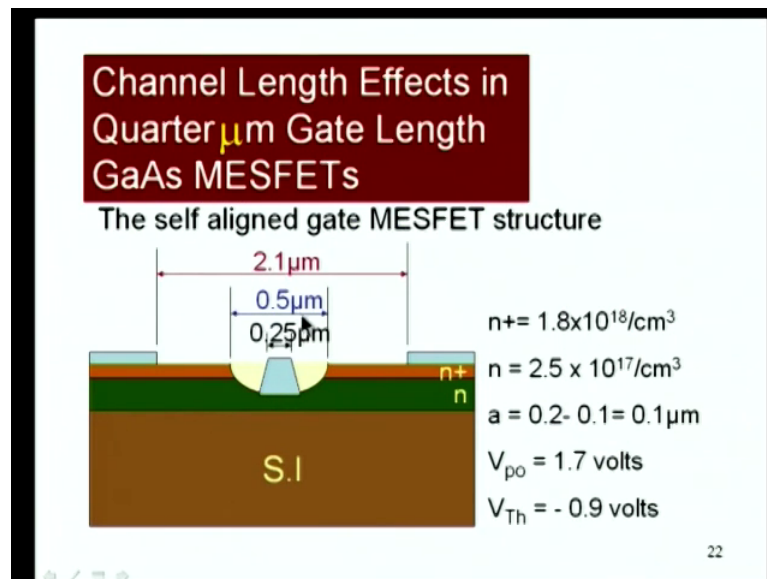
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So, this is the characteristics when we using the assuming that the channel drain current saturates when the depletion layer pinches off at the drain end, but if the channel bits are short this can happen even before pinch off takes place because of velocity saturation. So, I will not go into the details of that, but you can approximate by approximating the velocity field characteristics in this fashion he know that it is not like this either it goes then saturates or it goes up and comes down again gallium arsenide.

But Michael Shur in his a paper way back and even in a loop, it is written he has shown that we make this approximation you can convert that particular equation. And you can write it in a form for short channel devices in this fashion ID saturation is you can see all those terms are there w ; w is there, this is the c of s that is the capacitance of the channel silicon and L goes up when the velocity saturation takes place as just like in the case of the a MOSFET, because the mobility term gets absorbed in the velocity velocity saturation.

So, you get it is shown that you can write it in terms of this that is ID saturation is proportional to the channel capacitance that is the this quantity thinner that channel higher is the drain current thinner the current channel higher will be the trans conductance that is ΔI_D by ΔI_{GS} driving capability is better provided you have got enough careers there. So, that would actually need to increase the doping concentration also when they make the channel thickness smaller please that is changes slow.

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So, this is expression now this is deliberately drawn if I use velocity saturation as 10 to the power of 7 and if when I use this particular term which is a approximation to the entire characteristics saturating like this there is no velocity overshoot etcetera.

It goes on increasing saturates at 10 to the power of seven; that means, if I go to high field it is 10 to the power of 7 if I do that when I make a device do I get dual characteristics what velocities I will get do I get 10 to the power of 7 odd currents I get

what trace condense I get for some experiment people have done. So, to see how the channel length effects the quarter micrometer gate length gallium arsenide MESFETs people have made experiments see for example, here this is the whole thing is the channel length the green color there is the channel n region and this red color is n plus region on the top this is a semi insulating layer. And they have put the metal here ohmic contact is very easy to make ohmic contact on n plus region rather than on n; n region invariably they will have they should have n plus region there. Now I am not going to the technology of this, but what they have done is they have removed this material here ached this material they have ached this material it is a isotope aching removed this n plus layer removed this n layer also.

So, that the thickness of the channel is reduced originally what that; they started had n plus layer one 0.8 into 10 to the power eighteen. So, that even if you put a contact here at the end of this region it is very low resistance. So, when you apply voltage here I am sorry when you apply voltage here that is coming right up to this point because the drop across this region is negligible. So, whatever current is flowing which is collected here similarly whatever current injected here is injected into a channel here, but notice that there is some small gap between n plus and this because otherwise this you cannot have it connecting exactly touching this gate because then it will short. So, there are 2 things that they did it they wanted to study the effect of this n plus layer present.

Here with this n plus layer and without this n plus layer. So, this metal contact distance between them is 2.1 micron the portion where they achieved this n plus layer is 0.5 micron and this is actually the gate which is 0.25 micron is quarter wave it is this is quarter micro meter 0.25 micro meter gate; gate length channel length is more than the gate length means the contact ohmic contact is here n plus layer is here one plus layer here. So, you have a channel length which is more than the gate length 0.25 micron gate length 0.5 micron channel length. So, the thickness of this layer n layer was 0.2 microns, they have h 1 micron from here. So, that actual channel thickness is 0.1 micro meters. So, the pinch off voltage corresponding to this 0.2 micro meter thickness and doping 1.81 po 2.5 into 10 to the power seventeen doping here is that is by using that formula $qN D a^2$ by twice epsilon r epsilon 0.

You get that is a one point here 7 volts that is the pinch off voltage. So, now, what they did was they made the MOSFET with the n plus layer going all the way up to this point like this. So, in this case channel increase 0.25 microns gate length is 0.25 microns

suppose you h of this n plus layer from this end completely that is n plus layer is absent up to this point only in this point here just below this contact n plus then the channel length is from here to here that is 2.5 one micron. So, that second case is 2.1 micron channel length, but gate length is 0.25 micron. So, here we have got situation where one case channel length is 2.1 microns and in another case channel length is 0.5 microns in both cases gate length is 0.25 micron ok.

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Case i
n+ layer is etched so that,
the channel length = 2.1 μm
and gate length = 0.25 μm

Case ii
n+ layer is retained so that the Drain
and Source are close to Gate
Thus the channel length = 0.5 μm
and gate length = 0.25 μm

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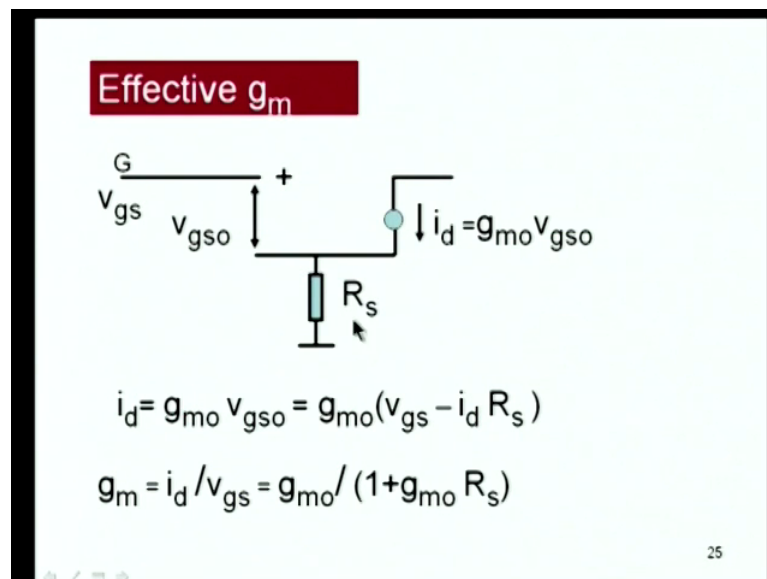
So, that is the situation they have done the case 2 n plus retained is one case is retained you retained n plus and the first case that is removed.

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Device No	Channel Structure	Gate Length μm	Channel Length μm	Observed g_m (eff) mA/V/mm
1	Without n^+	0.25	2.1	125
2	With n^+	0.25	0.5	215

So, they made measurements on that without n plus that is no n plus layer channel length is 2.1 micron and gate length is 0.25 micron, they observed g_m as 125 milli ampere per volt per millimeter channel width. Now when n plus layer was present and this layer was present they saw the g_m was much higher obvious it just got to be higher because if the n plus layer is not present you have got lot of resistance from here to here as we discussed in the case of MOSFET.

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Using this equivalent circuit there is a resistance between the edge of the channel and a

source contact is a gate source contact that resistance is coming from here to this channel length when this layer is present resistance is only be small here when the layer is absent channel length 2.1 micron the resistance is higher. So, that is R_s including that you will have g_m will be much smaller come because if the resistance is absent this is g_{m0} if the resistance is present it will be g_{m0} divided by $1 + g_{m0} R_s$, it is consist in case of MOSFET also.

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Device No	Source resistance R_s (Ohm)	Intrinsic g_m (eff) mA / V / mm	Effective Electron Velocity (cm/sec)
1 Without n^+	1.11	145	1.1×10^7
2 With n^+	0.56	245	1.9×10^7

The effective saturation velocity is higher than the saturation velocity – Clear case of Velocity Overshoot effect

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So, by incorporating this correction then they found incorporating this correction.

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High performance require higher drive current and high g_m

$$I_{DS} = 2c_s W v_s \frac{(V_{GS} - V_{Th})^2}{V_{po}}$$

$$g_m = 4c_s W v_s \frac{V_{GS} - V_{th}}{V_{Po}}$$

$$c_s = \frac{\epsilon_r \epsilon_o}{a}$$

The channel thickness should be small . This will have to be accompanied with high channel doping . Which leads to lower electron mobility.

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And using this equation μ_m is equal to this quantity they found of made the corrections and estimated the μ_m all these terms are known to you $V_{GS} - V_{th}$ everything is known they calculated the V_{sat} saturation velocity. So, they did that they found that without n^+ plus they got velocity of 1.1 into 10^7 after making the correction neglecting the resistance they got about 10^7 saturation velocity, but with the n^+ plus they got 1.9 into 10^7 this all that you do is measure μ_m substitute for all these known quantities $V_{GS} - V_{th}$ is known and find out V_{sat} velocity from that.

Since you have made correction for the resistor the difference in these 2 cases is when this is present carriers are injected straight away into this channel very close by when n^+ plus layer is present carriers are injected into the high field region suddenly there they can go through the velocity overshoot effect where as if this layer is not present the carriers are injected here in to the channel by a time, it has reached here it has reached its steady state saturation velocity because there is a drop here.

So, when this n^+ plus layer is not present the channel region here the under the gate region there is no velocity overshoot effect it has already reached the steady state value, but if this n^+ plus layer is present the carriers are injected right here into the gate where the fields are high. So, it go through velocity overshoot effect. So, what we are telling is the result from that is with gallium arsenide if plus force region n^+ plus is very close to the gate region carriers get injected into the channel cold right away into the channel, it suddenly experiences the effect of high field and it experiences the velocity overshoot effect. And the average velocity is that effect in the channel is much higher than 10^7 centimeter per second saturation velocity is 10^7 that is almost twice you get trans conductance almost twice you get velocity it almost twice you get frequency is almost twice all that happens.

So, that is telling you that gallium arsenide devices definitely have the merit particularly when you go to even as small as channel length which are about 0.25 microns you can do that now the question is whether you can get self-arranged structure that has been reported I am not going to discuss that you can get very self-aligned; self-aligned n^+ plus with respect to that you can get using tri layer gate structure bit more complicated. So, I am not discussing it right now because of shortage of time.

So, that is the story now what you are saying these if I have to have in summary gallium

arsenide has got high impact to get high velocity and high performance now if I want to get higher trans conductance you can get that short channel effect and increase the velocity saturation effective velocity it about twice center or 7, but for a given $w V_{GS}$ etcetera. I can increase the g_m by increasing the capacitance that can be done by increasing the by reducing the channel thickness, but reduction in channel; channel should be accompanied by increasing doping. So, that threshold voltage can be adjusted to the required value.

So, the ultimate thing is even here we are haunted by the problem of high dropping effect. So, what is the way to go? Use the modified structure, use gallium arsenide substrate where you can have carriers where there is no doping. That type of structure will discuss that is hetero structure devices and HEMPT. We will discuss in my next lecture.